Cleanliness Inspection Report - according to ISO 16232 (2007)

Date:	2010-Jul-06, 10:09:58 AM -04'00'	**Magnification:**	16X	**Units:**	microns		**Filter in mm**
Company:	Clemex	**Calibration:**	5.2288 µm/pixel	**Filter area:**	1322	47	
Department:	QA	**# Fields:**	55	**Covered area:**	1322	mm2	
User name:	Ben Gagnon	**Tot. mass of particles:**		mg	**Ratio:**	1.0	
Sample ID:	18	**# of components:**		**Mass / Component:**			
Wetted surface Ac:		cm2	**Wetted volume Vc:**		cm3	=> (For all components)	

Particle count data and Component cleanliness code (CCC)

Size class	B[a)]	C	D[b)]	E	F	G	H	I	J	K[c)]	**Fibers[d)] Count**
Size range (mic)	7.5 - 15	15 - 25	25 - 50	50 - 100	100 - 150	150 - 200	200 - 400	400 - 600	600 - 1000	> 1000	0
Blank count	(can be filled in manually or linked to an exported file)										**Total Particle**
Particle count (-blank)	-	12820	11517	3211	211	27	5	0	0	0	27791
Count for 1 filter	-	12822	11519	3211	211	27	5	0	0	0	27795
Standardised count C - component	--	12822	11519	3211	211	27	5	0	0	0	27795
Cleanliness Level	--	14	14	12	8	5	3	00	00	00	15

COMPONENT CLEANLINESS CODE => **CCC :** C (B--/C14/Db)14/E12/F8/G5/H3/I00/J00/Kc)00)

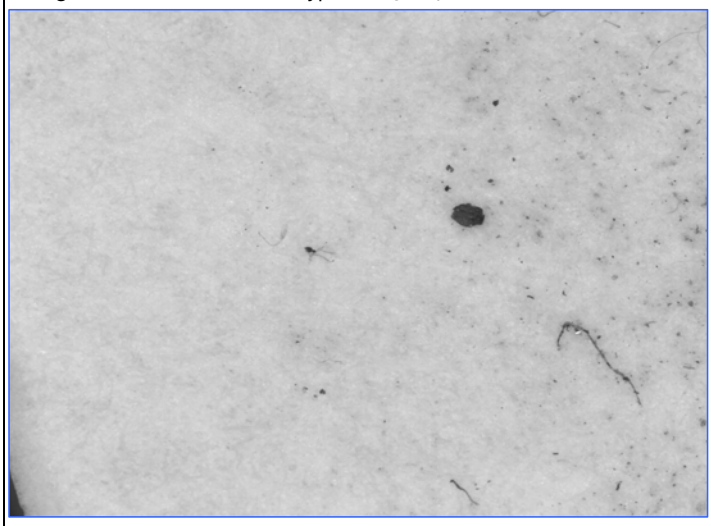
Global: C 15 Method: By cleanliness level

Notes:

a) At 16x, features smaller than 15 microns cannot be discriminated from artefacts and are not reported here.
b) At 16x, the precision decreases for particles under 50 microns. If a better precision is needed on smallest particles, use the routine for 55x instead.
c) Based on tiled features
d) Particles > 100 mic. with a String Length / String Width ratio > 30 (to be adjusted according to routine modification)

Remarks / Comments:

Image => Field type: Longest particle



Map view of the particles and fibers > 200 microns